

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	8	((test\$ near memory) (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/25 16:26
S1	11768	(test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and (conver\$5 near circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 23:48
S2	55309	test\$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:02
S3	36	test\$3 with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:02
S4	8	(test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and (conver\$5 near circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:18
S5	0	(test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and (conver\$5 near circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 23:48
		((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/738.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10

## EAST Search History

S6	1	((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/733.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S7	2	(BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S8	36	(BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S9	52	((test\$3 near memory) (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:12
S10	10	("4754215", "4862460", "5214654", "5314492", "5739778").pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/04/21 18:01
S11	2	"6065145".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/17 16:52
S12	1256	clock near align\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/17 16:52

## EAST Search History

S13	1370	clock near align\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/17 16:52
S14	9	(clock near align\$5) and (delay near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/17 16:53
S15	1987	yamada.in. and "integrated circuit"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/12/26 20:17
S16	2245	yamada.in. and "integrated circuit"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
S17	6	yamada.in. and "integrated circuit" and advantest.as.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
S18	0	(osamu and yamada).in. and "integrated circuit" and advantest.as.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
S19	38	(osamu and yamada).in. and "integrated circuit"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:18
S20	0	(osamu and yamada).in. and "integrated circuit" and (memory near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:19
S21	129	714/738.CCLS. and "integrated circuit" and (memory near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/26 20:19
S22	871	714/733.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:31

## EAST Search History

S23	3270	(714/733.ccls. 714/734.ccls. (built-in near test\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:32
S24	0	(714/733.ccls. 714/734.ccls. (built-in near test\$3)) and (neighborhood near sensitive near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:32
S25	2	(714/733.ccls. 714/734.ccls. (built-in near test\$3)) and (neighborhood near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:33
S26	24	(714/733.ccls. 714/734.ccls. (built-in near test\$3)) and (sensitive near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:46
S27	4	(714/733.ccls. 714/734.ccls. (built-in near test\$3)) and ((physical and logical) with (conver\$5))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/23 20:46
S28	3	"6815977".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:03
S29	29	(master and slave) with (scan adj cell)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:03
S30	1187	(master and slave) with (cell)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:03
S31	21	((master and slave) with (scan adj cell)) and (scan near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:04
S32	1914	(convert\$5 with physical with logical with address)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:58

## EAST Search History

S33	2	(convert\$5 with physical with logical with address) and (714/733.ccls. 714/734.ccls. (built-in near test\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/24 15:59
S34	871	714/733.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/24 17:23
S35	147	kato.in. and (crc)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/25 16:27
S36	48	kato.in. and (crc and packet)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/25 16:27
S37	0	kato.in. and (crc and packet).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/25 16:27
S38	48	kato.in. and (crc and packet)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/25 16:27
S39	5	kato.in. and (crc and packet) and BCH	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/25 16:28
S40	1450	714/758.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/25 16:28